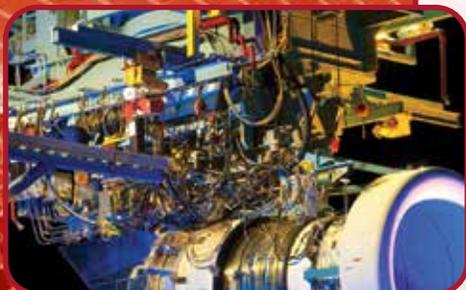
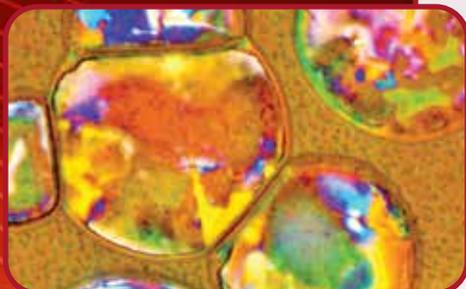


JOM Call for papers

An official publication of The Minerals, Metals & Materials Society



Publication Date: *September 2022*

Manuscript Deadline: *March 1, 2022*

Beam Induced Artifacts in Electron and Ion Beam Microscopy

Papers are invited to discuss various aspects of potential defects that may be introduced in electron and ion beam microscopy, and mitigation strategies. This includes SEM, TEM and FIB microscopy. Potential focus areas include but are not limited to artifacts resulting from beam damage, beam heating, beam-induced phase transformation, etc..

Original research papers should be 3,000-9,000 words with up to 12 figures maximum; review papers should be 6,000-11,000 words with up to 20 figures maximum.

Detailed author instructions are available at:
<http://www.tms.org/AuthorTools/>

Keywords for this topic: **Characterization; Experimental Methods; Artifact**

Guest Editor(s): Jian Li:
jian.li@canada.ca

Committee Sponsor(s): **Materials Characterization**

If you are interested in submitting a paper, upload your manuscript at
<https://www.editorialmanager.com/jomj/>

Please note that all submissions will be subject to peer review. Submission does not guarantee acceptance.

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